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United States Patent [19]

Aukstikalnis et al.

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[54] **ELECTRICAL TEST PROBE**

[75] Inventors: **Glen Aukstikalnis**, Vancouver; **Mark Nightingale**, Camas, both of Wash.

[73] Assignee: **Tektronix, Inc.**, Wilsonville, Oreg.

[**] Term: **14 Years**

[21] Appl. No.: **538,941**

[22] Filed: **Jun. 13, 1990**

[52] **U.S. Cl.** **D10/80**

[58] **Field of Search** .... D10/80, 103, 46; 29/844, 847, 862; 174/89, 750; 324/72.5, 156, 149, 158 P; 439/482, 585, 374, 824, 819

[56] **References Cited**

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Primary Examiner—Alan P. Douglas
Assistant Examiner—Antoine Davis
Attorney, Agent, or Firm—William K. Bucher

[57] **CLAIM**

The ornamental design for an electrical test probe, as shown.

DESCRIPTION

FIG. **1** is a perspective view of an electrical test probe showing our new design;

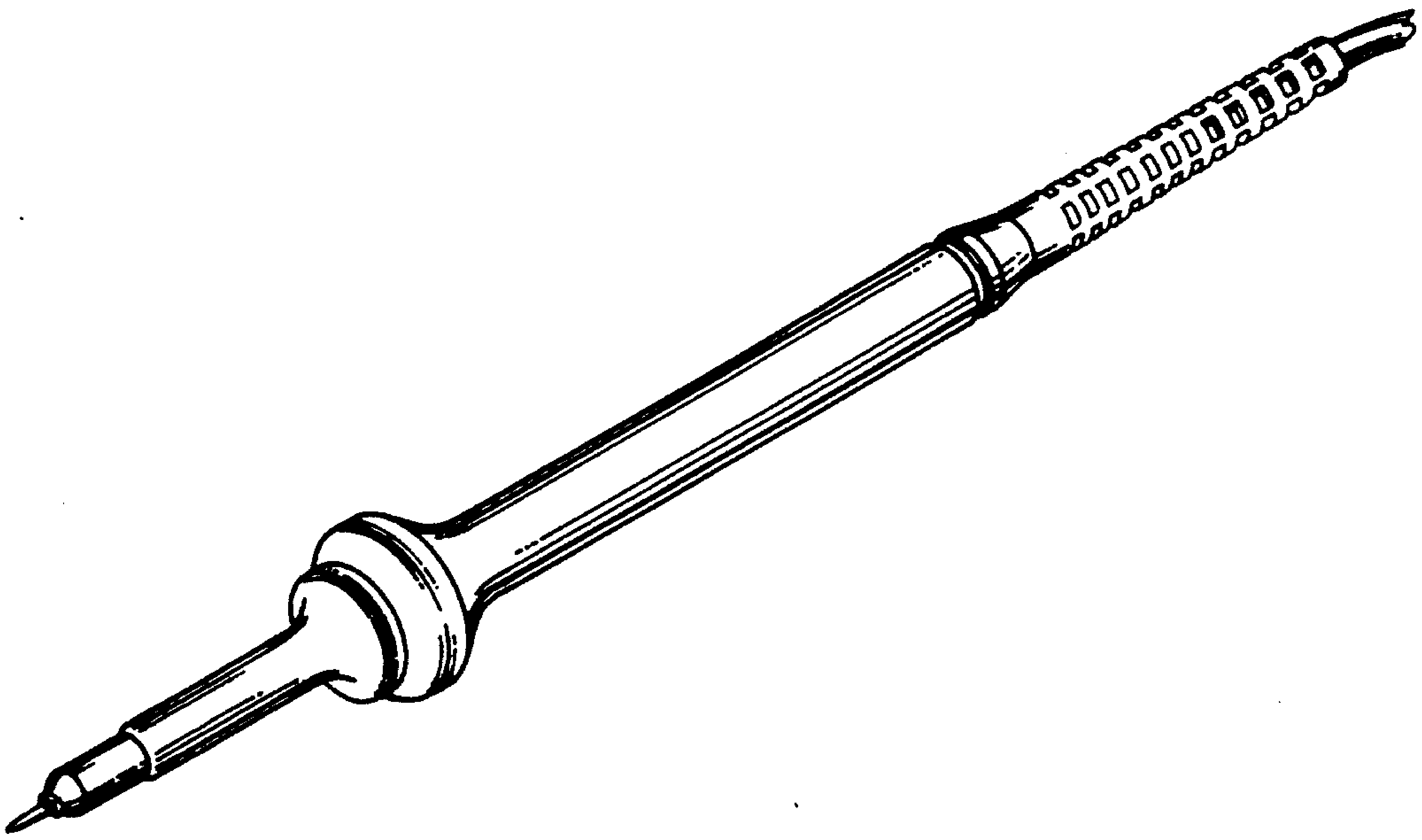
FIG. **2** is a left side elevational view thereof, the right side elevational view being a mirror image;

FIG. **3** is a top plan view thereof;

FIG. **4** is a bottom plan view thereof;

FIG. **5** is a front elevational view thereof; and,

FIG. **6** is a rear elevational view thereof.



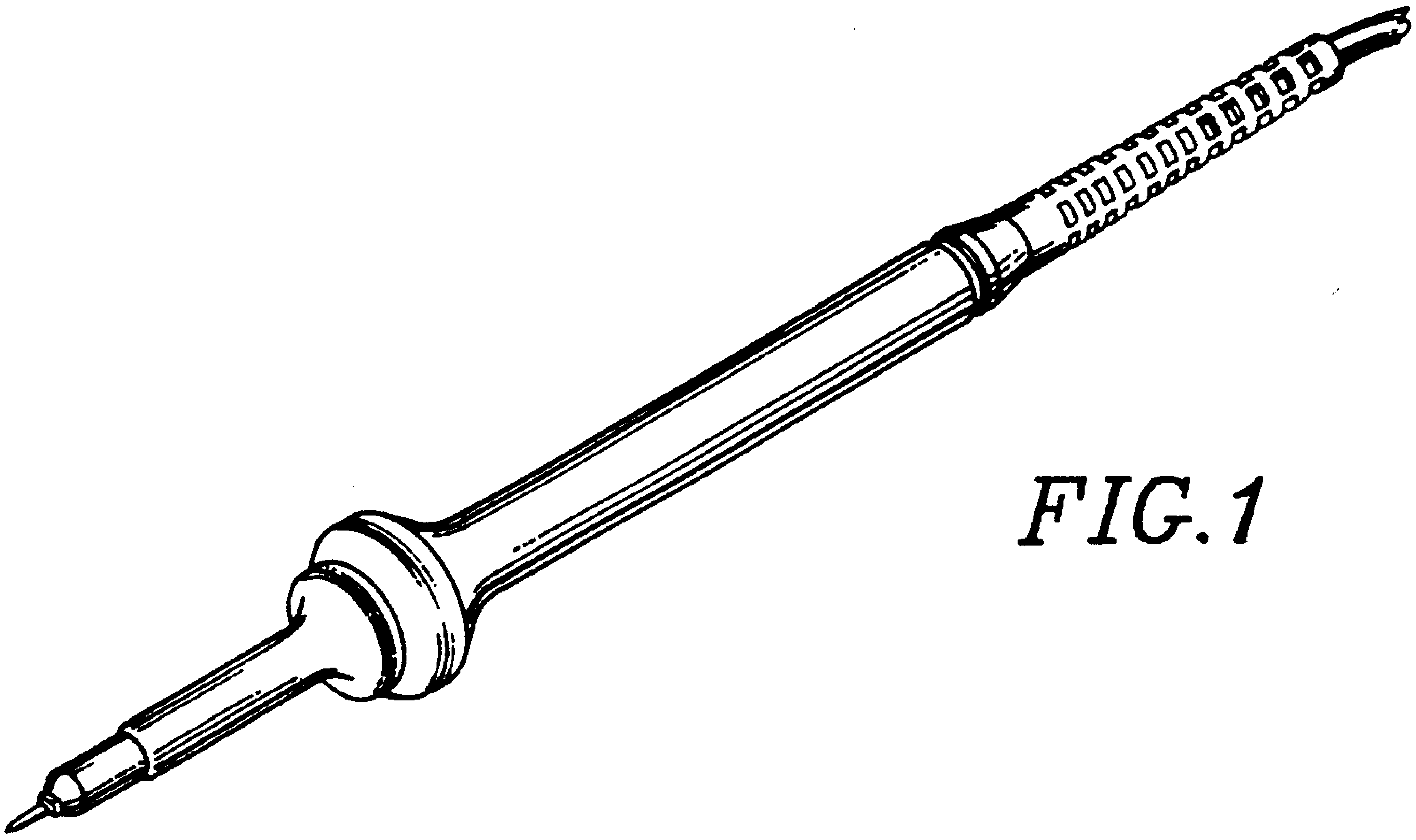


FIG. 1

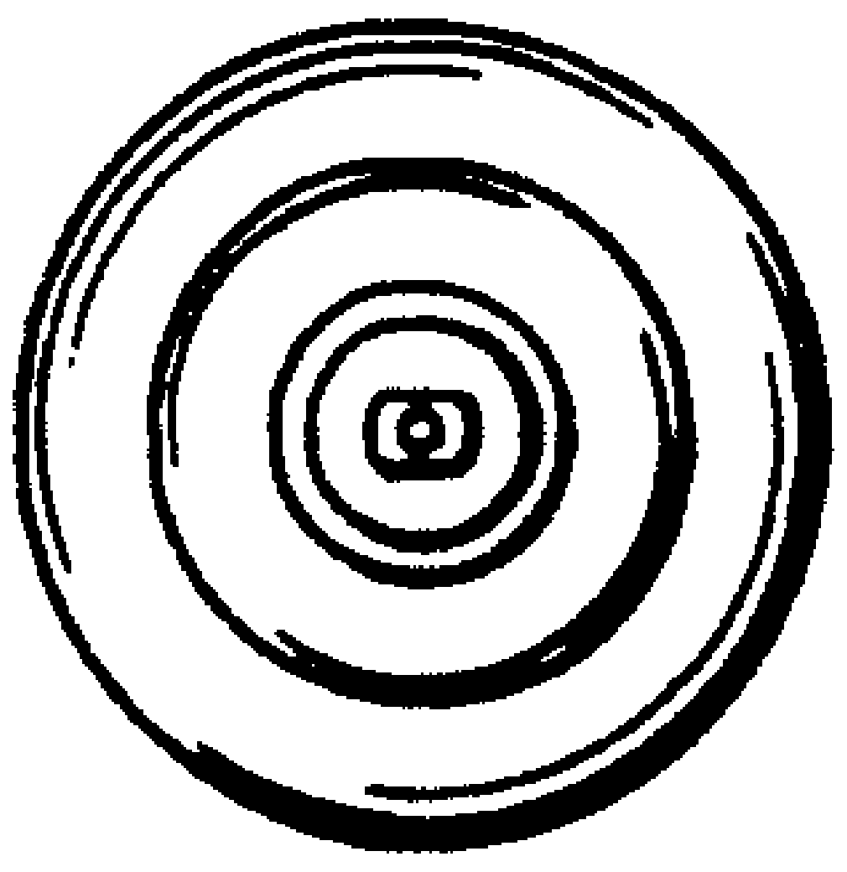


FIG. 6

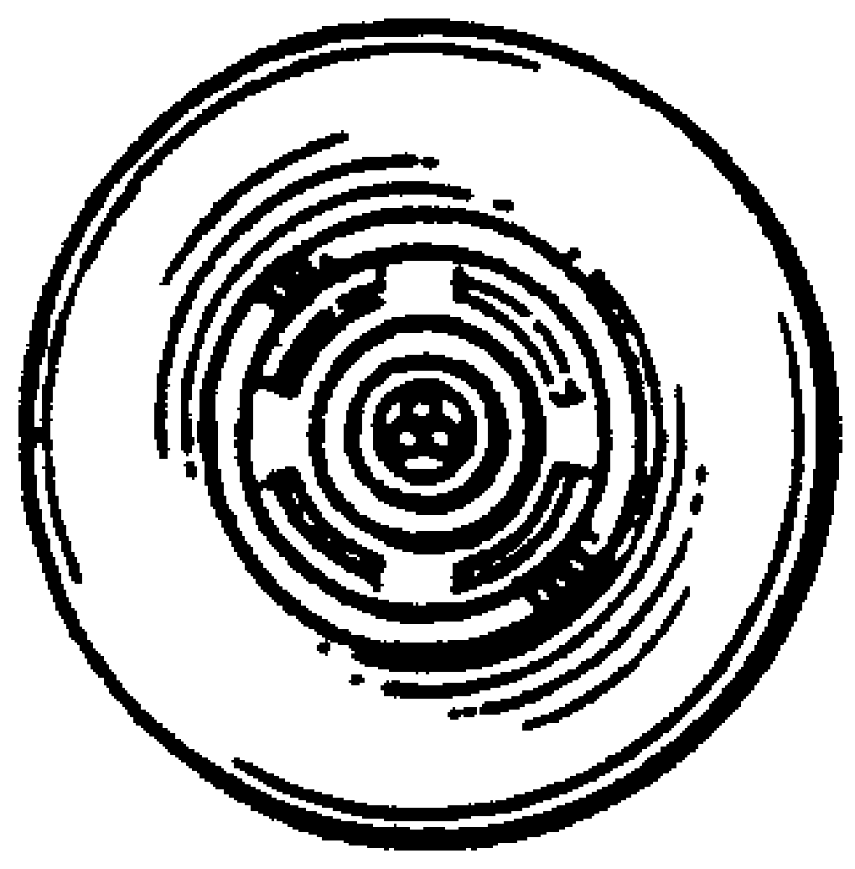


FIG. 5

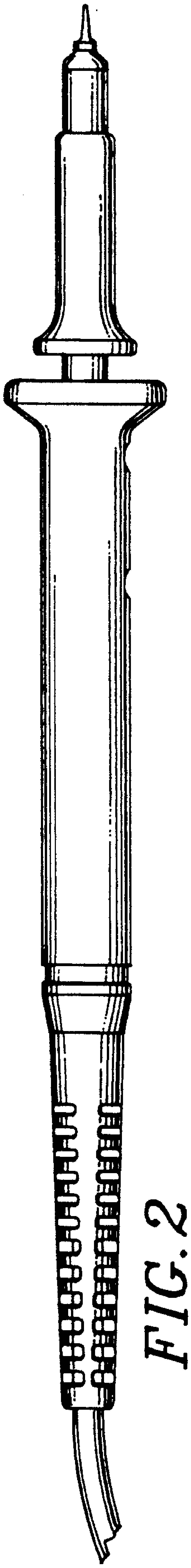


FIG. 2

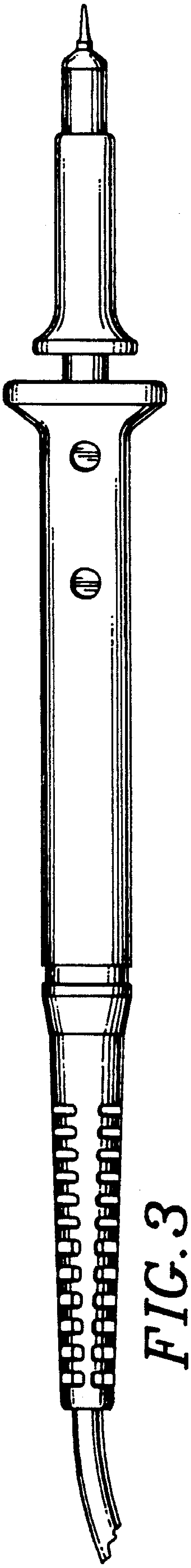


FIG. 3

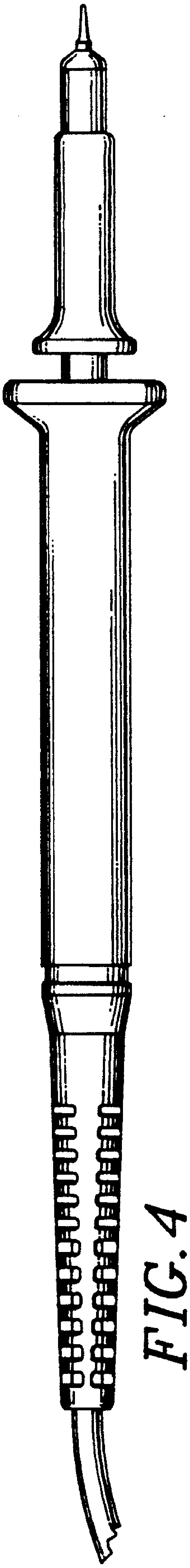


FIG. 4